PCN Number:		20210903001.1						PCN Date:		September 27, 2021	
Title: Qualification of CDAT as an alternate Assembly site for Select Devices											
Customer Contact: PCN Manager Dept: Quality Services											
Propose	d 1 st Shi	p Date:	p Date: Dec 27							e provided at	
				Avai			llat	lability: sample request			
Change Type: Design Wafer Bump Site Assembly Site Design Wafer Bump Site						n Site					
Assembly Site				ta Sheet			Wafer Bump Material				
Assembly Materials					t number change			Wafer Bump Process			
Mechanical Specification					st Site			Wafer Fab Site			
Pack	ping/Labe	/Labeling 🔄 Te			ocess		Wafer Fab Materials				
				D				Wafer Fab Process			
PCN Details Description of Change:											
Descript		nanye:									
Texas Instruments Incorporated is announcing the qualification of CDAT as an additional Assembly site for the list of devices shown below. Construction differences between the 2 sites are as follows:											
	c					TI Clark	TI Clark C		DAT		
	n	Mold Com	bound			4208625 422			8		
Reason	for Char	nge:	je:								
Supply continuity											
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):											
None											
Impact on Environmental Ratings											
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.											
RoHS			EACH		Green Stat	Green Status		_	C 62474		
🛛 No Change		\square	🛛 No Chang			🛛 No Change		🛛 🖂 No C		hange	
Changes to product identification resulting from this PCN:											
Assemb	oly Site	Assembly	igin (22L)) Assembly Country Co		ode (23L)		Ass	sembly City		
TI C	lark				PHL	Angeles		geles	City, Pampanga		
CD	AT		CDA			CHN			Chengdu		
Sample product shipping label (not actual product label)											

OPT .	/29/04	LA	
LBL: 5A (L)TO:1	/50): MYS	
LBL: 5A (L)T0:1 Product Affected:	/50		
	750 TPS659162RGZT		1



TI Information Selective Disclosure

Approved 12-Aug-2021

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

but bisplayed as. Number of fots / fotal sample size / fotal failed							
Туре	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: 0917A130TRGZRQ1	Pkg QBS Device: LM2775QDSGRQ1
HAST	JEDEC JESD22- A110	3	77	Biased HAST, 130C/85%RH	96 hours	1/77/0	3/231/0
AC	JEDEC JESD22- A102	3	77	Autoclave 121C	96 hours	1/77/0	3/231/0
тс	JEDEC JESD22- A104 and Appendix 3	3	77	Temperature Cycle, - 65/150C	500 cycles	1/77/0	3/231/0
HTSL	JEDEC JESD22- A103	1	45	High Temp Storage Bake 175C	1000 hours	1/45/0	3/132/1*
HTOL	JEDEC JESD22- A108	3	77	Life Test, 125C	1000 hours	1/77/0	3/231/0
WBS	-	1	30	Wire Bond Shear (Cpk>1.67)	Wires	1/30/0	3/90/0
WBP	MIL-STD883 Method 2011	1	30	Wire Bond Pull (Cpk>1.67)	-	-	3/90/0
SD	JEDEC JESD22- B102	1	15	Surface Mount Solderability >95% Lead Coverage	-	-	3/45/0
PD	JEDEC JESD22- B100 and B108	3	10	Physical Dimensions (Cpk>1.67)	Cpk>1.67	1/10/0	3/90/0
CDM	-	1	3	ESD - CDM - Q100	1000 V	1/3/0	
Char	-	3	30	Electrical Char	Cpk>1.67	3/90/0	3/90/0
MSL		-	-	Moist Sens. L3	(MSL 3 / 260C)	1/22/0	

QBS: Qual By Similarity
 Qual Device 0917A130TRGZRQ1 is qualified at LEVEL3-260CG

A1 (PC): Preconditioning: Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level: Grade 0 (or E): -40°C to +150°C Grade 1 (or Q): -40°C to +125°C Grade 2 (or T): -40°C to +105°C Grade 3 (or I): -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples: Room/Hot/Cold: HTOL, ED

Room/Hot: THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU Room: AC/uHAST

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

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USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
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